



WTW2007 6th Workshop on Test of Wireless Circuits and Systems

Claremont Resort, Berkeley, California, USA

May 6th, 2007

In Conjunction with VTS07



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Call for Papers

Scope

The Wireless Test Workshop (WTW2007) is an IEEE-sponsored workshop devoted to exploring all issues relating to the design and especially test of wireless circuits and systems. The workshop will be held the day before the VLSI Test Symposium (VTS) 2007.

All topics relating to design and test of RF circuits and systems are of interest, including:

- Design-for-testability
- RF wafer probing
- High frequency test
- Yield learning and analysis
- Wireless test methodology
- Case studies
- Wireless system test
- Embedded RF circuit test
- Standards conformance test
- Design characterization and validation
- Noise analysis and avoidance
- Design-for-manufacturability
- Test board related issues
- Test equipment and metrology
- Alternative test methods
- Cost of test
- Fault diagnosis and failure analysis

Tutorial and panel proposals will also be considered.

Author information

To present recent results at the workshop, please submit an extended abstract of between 500 and 1000 words to the program chair (PDF or Word versions through email are preferred). The abstract should clearly describe the nature of the contribution, the method, results, originality, significance, and superiority over other methods. The name, address, phone number, fax number, and email address of the presenter should also be included. Informal proceedings of the workshop will be distributed to attendees.

Submissions are due no later than **March 2nd, 2007**.

Please submit your paper proposal to the Program Chair at:

- Mustapha Slamani, IBM, slamanim@us.ibm.com, Tel: +1 802.769.0676, Fax: +1 802.769.7509

Authors will be notified of the disposition of their papers by **March 23rd, 2007**.

Authors of accepted papers are asked to submit a camera ready full paper by **April 6th, 2007** for inclusion in the Digest of Papers, which will be provided to the attendees.

WTW 2007 is sponsored by the IEEE Computer Society Test Technology Technical Council (TTTC).

For more information on WTW-2007, visit the workshop website at:

www.wtw2007.tec.ufl.edu

